# **Power MOSFET**

# 30 V, 23 A, Single N-Channel, SO-8 Flat Lead

#### **Features**

- Low R<sub>DS(on)</sub>
- Low Inductance SO-8 Package
- This is a Pb-Free Device

#### **Applications**

- Notebooks, Graphics Cards
- DC-DC Converters
- Synchronous Rectification

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit	
Drain-to-Source Voltage			V <sub>DSS</sub>	30	V	
Gate-to-Source Voltage			$V_{GS}$	±20	V	
Continuous Drain Current	Steady T <sub>A</sub> = 25°		I <sub>D</sub>	14	Α	
(Note 1)	State	T <sub>A</sub> = 85°C		10		
	t ≤10 s	T <sub>A</sub> = 25°C		23		
Power Dissipation (Note 1)	Steady State T <sub>A</sub> = 25°C		P <sub>D</sub>	2.2	W	
	t ≤10 s			5.8		
Continuous Drain Current	0	T <sub>A</sub> = 25°C	I <sub>D</sub>	9.1	Α	
(Note 2)	Steady State	T <sub>A</sub> = 85°C		6.5		
Power Dissipation (Note 2)		$T_A = 25^{\circ}C$	$P_{D}$	0.9	W	
Pulsed Drain Current	t <sub>p</sub> =	10 μs	I <sub>DM</sub>	68	Α	
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	–55 to 150	°C	
Source Current (Body Diode)			IS	7.0	Α	
Single Pulse Drain-to-Source Avalanche Energy ( $V_{DD}$ = 30 V, $V_{GS}$ = 10 V, $I_{PK}$ = 21 A, L = 1 mH, $R_G$ = 25 $\Omega$ )			E <sub>AS</sub>	220	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C	

### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	56.3	°C/W
Junction-to-Ambient - t ≤ 10 s (Note 1)	$R_{\theta JA}$	21.5	
Junction-to-Ambient - Steady State (Note 2)	R <sub>0.1A</sub>	141.6	

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

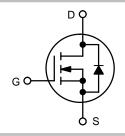
- 1. Surface mounted on FR4 board using 1 in sq pad size (Cu area = 1.127 in sq [1 oz] including traces).
- Surface mounted on FR4 board using the minimum recommended pad size (Cu area = 0.0264 in sq).



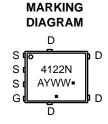
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V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> TYP	I <sub>D</sub> MAX (Note 1)
30 V	4.6 mΩ @ 10 V	23 A
	6.3 mΩ @ 4.5 V	2570







4122N = Specific Device Code A = Assembly Location

Y = Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS4122NT1G	SO-8 FL (Pb-Free)	1500 Tape & Reel
NTMFS4122NT3G	SO-8 FL (Pb-Free)	5000 Tape & Reel

- †For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.
- \*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

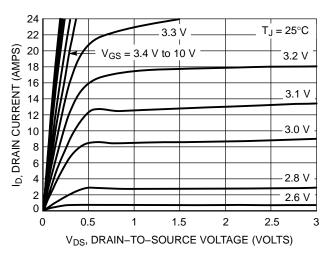
## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Characteristic	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•					1	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				23		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		T <sub>J</sub> = 25°C			1.0	μΑ
		$V_{GS} = 0 \text{ V}, V_{DS} = 24 \text{ V}$	T <sub>J</sub> = 125°C			10	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} =$	= 20 V			100	nA
ON CHARACTERISTICS (Note 3)							-
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}$ , $I_D = 2$	250 μΑ	1.0		2.5	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				6.6		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> =	= 14 A		4.6	6.0	mΩ
		V <sub>GS</sub> = 4.5 V, I <sub>D</sub> =	= 12 A		6.3	8.5	
Forward Transconductance	9FS	V <sub>DS</sub> = 15 V, I <sub>D</sub> =	= 10 A		13.2		S
CHARGES, CAPACITANCES AND GATE R	ESISTANCE			•	-	-	•
Input Capacitance	C <sub>ISS</sub>				2310		pF
Output Capacitance	Coss	V <sub>GS</sub> = 0 V, f = 1.0 MHz	, V <sub>DS</sub> = 24 V		460		1
Reverse Transfer Capacitance	C <sub>RSS</sub>	25			263		1
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 15 V, I <sub>D</sub> = 12 A			20	30	nC
Threshold Gate Charge	Q <sub>G(TH)</sub>				3.0		
Gate-to-Source Charge	Q <sub>GS</sub>				6.7		
Gate-to-Drain Charge	$Q_{GD}$				8.1		
Gate Resistance	$R_{G}$				0.7		Ω
SWITCHING CHARACTERISTICS (Note 4)							-
Turn-On Delay Time	t <sub>d(ON)</sub>				20		ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> :	= 15 V.		20		1
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = 1.0 \text{ A}, R_L = 15 \Omega, R_G = 3.0 \Omega$			30		
Fall Time	t <sub>f</sub>				31		
DRAIN-SOURCE DIODE CHARACTERISTI	cs						•
Forward Diode Voltage	V <sub>SD</sub>	\/oo = 0 \/ lo = 7 0 A	T <sub>J</sub> = 25°C		0.75	1.0	V
			T <sub>J</sub> = 125°C		0.6		7
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, dI}_S/\text{dt} = 100 \text{ A/}\mu\text{s,}$ $I_S = 7.0 \text{ A}$			28		ns
Charge Time	ta				14		1
Discharge Time	t <sub>b</sub>				14		
Reverse Recovery Charge	Q <sub>RR</sub>				23		nC

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL PERFORMANCE CURVES**

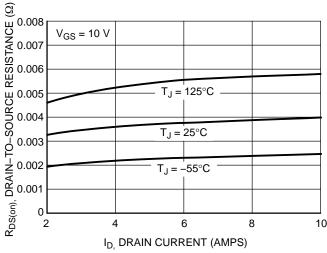
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 $V_{DS} = 30 \text{ V}$ 22 ID, DRAIN CURRENT (AMPS) 20 18 16 14 12 10 8  $T_J = 125^{\circ}C$ 6 4  $T_J = 25^{\circ}C$ 2  $T_J = -55^{\circ}C$ 0 2 4 5 1 V<sub>GS</sub>, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



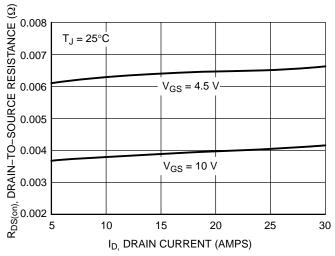
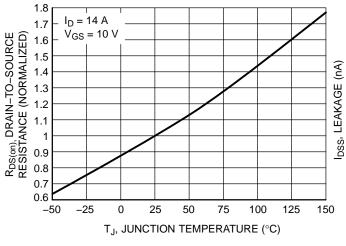


Figure 3. On-Resistance vs. Drain Current

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



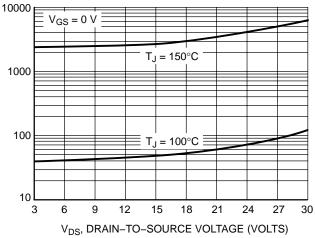


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL PERFORMANCE CURVES**

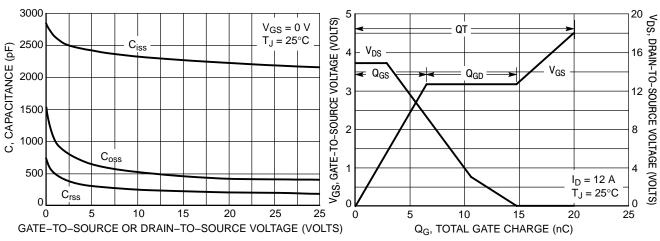


Figure 7. Capacitance Variation

Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

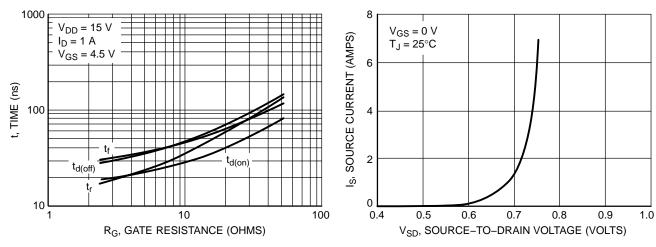


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current

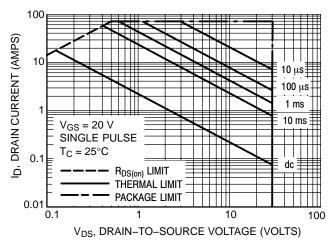
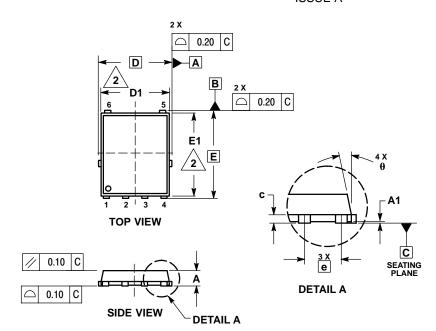
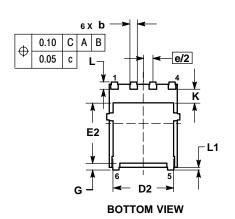


Figure 11. Maximum Rated Forward Biased Safe Operating Area

#### **PACKAGE DIMENSIONS**

#### **SO-8 FLAT LEAD** CASE 488AA-01 **ISSUE A**





- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETER.
  3. DIMENSION DI AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS				
DIM	MIN	NOM	MAX		
Α	0.90	0.99	1.20		
A1	0.00		0.05		
b	0.33	0.41	0.51		
С	0.23	0.28	0.33		
D	5.15 BSC				
D1	4.50	4.90	5.10		
D2	3.50		4.22		
Е	6.15 BSC				
E1	5.50	5.80	6.10		
E2	3.45		4.30		
е	1.27 BSC				
G	0.51	0.61	0.71		
K	0.51				
١	0.51	0.61	0.71		
L1	0.05	0.17	0.20		
θ	0 °		12 °		

- STYLE 1: PIN 1. SOURCE 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN

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